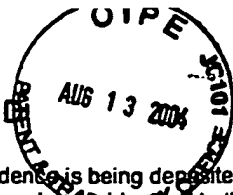


Docket No.: PEK-In1163



IFW

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By: W. Asam

Date: August 10, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applic. No. : 10/751,316 Confirmation No: 1985
Applicant : Wilhelm Asam et al.
Filed : January 2, 2004
Title : Method for Detecting the Reliability of Integrated Semiconductor
Components at High Temperatures
Art Unit : 2826
Examiner : Scott R. Wilson

Docket No. : PEK-In1163 D
Customer No. : 24131

Letter under 37 C.F.R. §1.312

Hon. Commissioner for Patents

Sir:

In the IDS filed on January 2, 2004 German Patent DE 198 41 202 C1 (Gärtner et al.), dated March 2, 2000 was cited. The patent had been originally submitted in an IDS in parent application 10/200,934 on August 16, 2002. Inadvertently, this German patent was not listed on Form PTO-1449.

Applicants are submitting herewith a copy of German Patent DE 198 41 202 C1, corresponding U.S. Patent No. 6,255,892 B1 and Form PTO-1449.